Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	•
09/903,521	NAKAMURA, SATOSHI	
Examiner	Art Unit	
Nhan T. Tran	2615	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
UPDATED EAST (USPAT, US- PGPUB, EPO, JPO. WERWENT)	6/24/2005	NT		
348/222.1, 234-238 (text search - see Searh History printout)	6/24/2005	NT		
348/223.1 (text search - see Search History printout)	6/24/2005	NT		
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